Notice of References Cited Application/Control No. 10/626,674 Examiner Christian A. Hannon Applicant(s)/Patent Under Reexamination KIM ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2005/0107131	05-2005	Abramov, Igor	455/569.1
*	В	US-6,249,684	06-2001	Hasegawa, Yutaka	455/575.3
*	С	US-6,192,221	02-2001	Hasegawa, Yutaka	455/575.3
*	D	US-2005/0208980	09-2005	Tsai et al.	455/569.1
*	Ε	US-2005/0153748	07-2005	Bodley, Martin Reed	455/569.1
*	F	US-2004/0204207	10-2004	Parker, John A.	455/575.2
*	G	US-2002/0111197	08-2002	Fitzgerald, Robert M.	455/568
*	Н	US-6,010,216	01-2000	Jesiek, Daniel Stephen	351/158
*	ı	US-6,230,029	05-2001	Hahn et al.	455/575.2
*	J	US-2003/0119565	06-2003	Lin, Ming Hsun	455/569
*	κ	US-2002/0111140	08-2002	Kim, Dong-Woo	455/41
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					·
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.